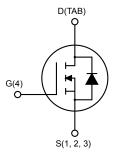


Automotive-grade N-channel 40 V, 1.6 mΩ typ., 100 A, STripFET™ F7 Power MOSFET in an LFPAK 5x6 package

TAB 34

LFPAK 5x6



G4S123DTAB_LFPAK



Product status link	
STK184N4F7AG	

Product summary				
Order code STK184N4F7AG				
Marking	184N4F7AG			
Package	LFPAK 5x6			
Packing	Tape and reel			

Features

Order code	V _{DS}	R _{DS(on)} max.	I _D
STK184N4F7AG	40 V	2.0 mΩ	100 A

- AEC-Q101 qualified
- Among the lowest R_{DS(on)} on the market
- Excellent FoM (figure of merit)
- Low C_{rss}/C_{iss} ratio for EMI immunity
- · High avalanche ruggedness

Applications

Switching applications

Description

This N-channel Power MOSFET utilizes STripFET™ F7 technology with an enhanced trench gate structure that results in very low on-state resistance, while also reducing internal capacitance and gate charge for faster and more efficient switching.



1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	40	V
V _{GS}	Gate-source voltage	±20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	100	Α
ID(,,)	Drain current (continuous) at T _C = 100 °C	100	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	400	Α
P _{TOT}	Total power dissipation at T _C = 25 °C	136	W
I _{AV}	Avalanche current, repetitive or not repetitive (pulse width limited by maximum junction temperature)	42	А
E _{AS}	Single pulse avalanche energy (starting $T_J = 25$ °C, $I_D = I_{AV}$, $V_{DD} = 25$ V)	280	mJ
Tj	Operating junction temperature range	FF 1- 47F	°C
T _{stg}	Storage temperature range	-55 to 175	

^{1.} Drain current is limited by package, the current capability of the silicon is 184 A at 25 °C.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-pcb} ⁽¹⁾	Thermal resistance junction-pcb	31.3	°C/W
R _{thj-case}	Thermal resistance junction-case	1.1	°C/W

1. When mounted on FR-4 board of 1 inch 2 , 2oz Cu, t < 10 s.

DS12627 - Rev 2 page 2/13

^{2.} Pulse width limited by safe operating area.



2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	40			V
I _{DSS}	Zero gate voltage drain current	V _{GS} = 0 V, V _{DS} = 40 V			1	μΑ
I _{GSS}	Gate-body leakage current	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2		4	V
R _{DS(on)}	Static drain-source on-resistance	V _{GS} = 10 V, I _D = 50 A		1.6	2.0	mΩ

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance	V _{DS} = 25 V, f = 1 MHz,	-	2750	-	pF
C _{oss}	Output capacitance	V _{DS} = 25 V, 1 = 1 IVITIZ,	-	625	-	pF
C _{rss}	Reverse transfer capacitance	- v _{GS} - ∪ v	-	200	-	pF
Qg	Total gate charge	V _{DD} = 20 V, I _D = 100 A,	-	35	-	nC
Q _{gs}	Gate-source charge	V _{GS} = 0 to 10 V	-	16	-	nC
Q _{gd}	Gate-drain charge	(see Figure 13. Test circuit for gate charge behavior)	-	8.9	-	nC

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V_{DD} = 20 V, I_D = 50 A, R_G = 4.7 Ω , V_{GS} = 10 V (see Figure 12. Test circuit for resistive load switching times and Figure 17. Switching time waveform)	-	12	-	ns
t _r	Rise time		-	20	-	ns
t _{d(off)}	Turn-off delay time		-	33.4	-	ns
t _f	Fall time		-	20.7	-	ns

Table 6. Source-drain diode

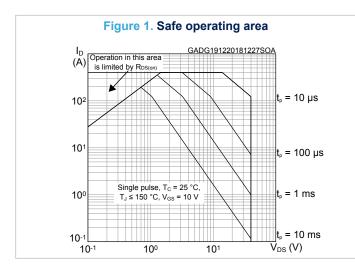
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{SD} ⁽¹⁾	Forward on voltage	I _{SD} = 100 A, V _{GS} = 0 V	-		1.1	V
t _{rr}	Reverse recovery time	I _D = 100 A, di/dt = 100 A/μs	-	25		ns
Q _{rr}	Reverse recovery charge	V _{DD} = 20 V	-	9.5		nC
I _{RRM}	Reverse recovery current	(see Figure 14. Test circuit for inductive load switching and diode recovery times)	-	0.8		А

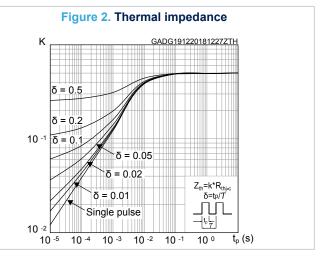
^{1.} Pulsed: pulse duration = 300 μs, duty cycle 1.5%

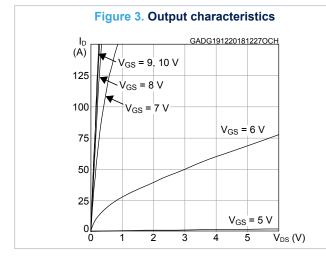
DS12627 - Rev 2 page 3/13

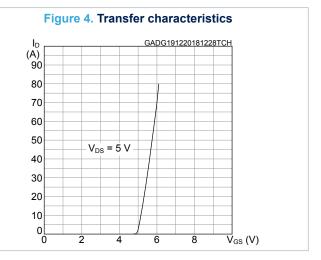


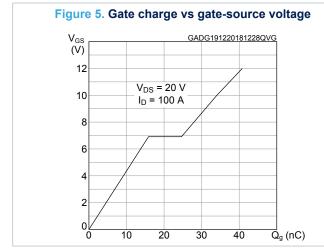
2.1 Electrical characteristics (curves)

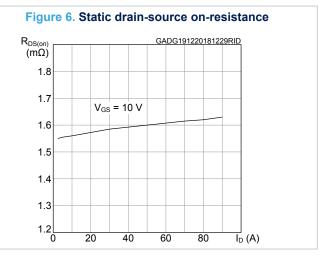












DS12627 - Rev 2 page 4/13



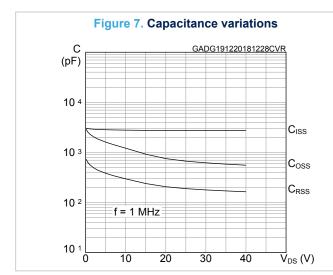
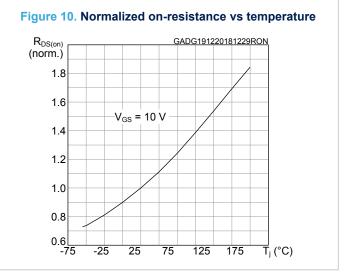
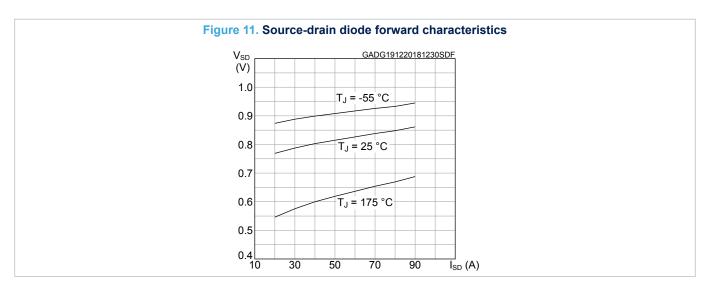


Figure 8. Normalized V_{(BR)DSS} vs temperature $V_{(BR)DSS} \\$ GADG191220181230BDV (norm.) 1.08 1.06 1.04 $I_D = 1 \text{ mA}$ 1.02 1.00 0.98 0.96 0.94 -75 25 75 175 -25 125 T_j (°C)

Figure 9. Normalized gate threshold voltage vs temperature GADG191220181547VTH $V_{GS(th)}$ (norm.) 1.2 1.0 0.8 $I_D = 250 \, \mu A$ 0.6 0.4 0.2 -75 25 175 T_j (°C) -25 75 125





DS12627 - Rev 2 page 5/13



3 Test circuits

Figure 12. Test circuit for resistive load switching times

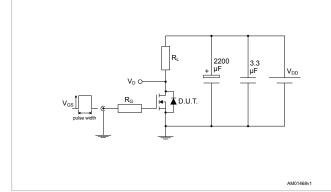


Figure 13. Test circuit for gate charge behavior

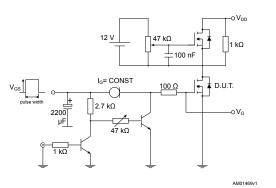


Figure 14. Test circuit for inductive load switching and diode recovery times

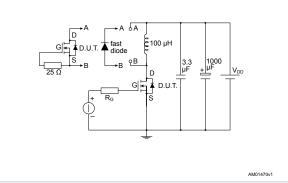


Figure 15. Unclamped inductive load test circuit

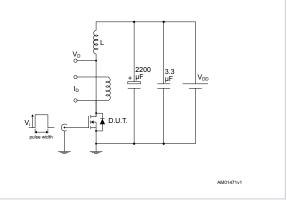


Figure 16. Unclamped inductive waveform

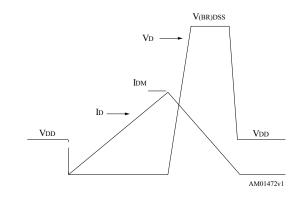
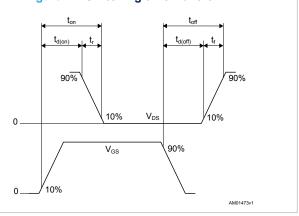


Figure 17. Switching time waveform



DS12627 - Rev 2 page 6/13



4 Package information

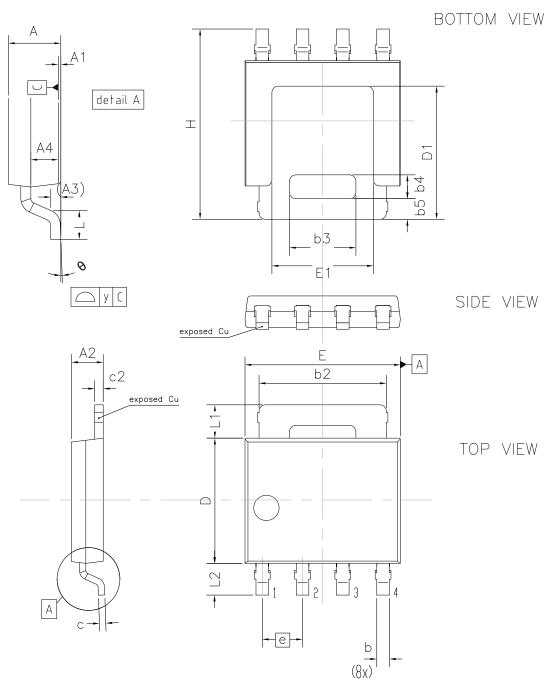
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

DS12627 - Rev 2 page 7/13



4.1 LFPAK 5x6 package information

Figure 18. LFPAK 5x6 package outline



00299525_A

DS12627 - Rev 2 page 8/13



Table 7. LFPAK 5x6 package mechanical data

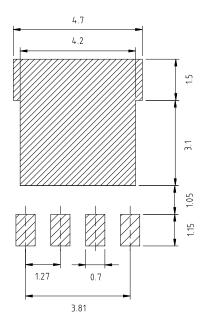
Div		mm	
Dim.	Min.	Тур.	Max.
А	1.01		1.20
A1	0.00		0.15
A2	0.95		1.10
A3		0.25	
A4	0.50	0.55	0.65
b	0.35		0.50
b2	3.62		4.41
b3	2.0		2.20
b4	0.70		0.90
b5			0.7
С	0.19	0.20(1)	0.25
c2	0.24		0.30
D	3.80		4.10
D1	3.80	4.00	4.20
E	4.8		5.0
E1	3.1		3.3
е		1.27	
Н	5.8		6.2
L	0.40		0.85
L1	0.80		1.30
L2	0.80		1.3
w		0.25	
у		0.10	
θ	0°		8°

^{1.} Dimension without plating

DS12627 - Rev 2 page 9/13



Figure 19. LFPAK 5x6 recommended footprint



00299525_FP_A

DS12627 - Rev 2 page 10/13



Revision history

Table 8. Document revision history

Date	Revision	Changes
05-Jul-2018	1	First release.
10-Jan-2019	2	Updated title and features on cover page.
		Updated Section 1 Electrical ratings and Section 2 Electrical characteristics.
		Added Section 2.1 Electrical characteristics (curves).
		Minor text changes

DS12627 - Rev 2 page 11/13



Contents

1	Elec	ctrical ratings	2
2	Elec	ctrical characteristics	3
	2.1	Electrical characteristics (curves)	4
3	Test	circuits	6
4	Pac	kage information	7
	4.1	LFPAK 5x6 package information	7
Rev	/ision	history	.11



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DS12627 - Rev 2 page 13/13